

Nondestructive Testing for SCC Crack Mapping and Depth Sizing

GridStation® IN8200

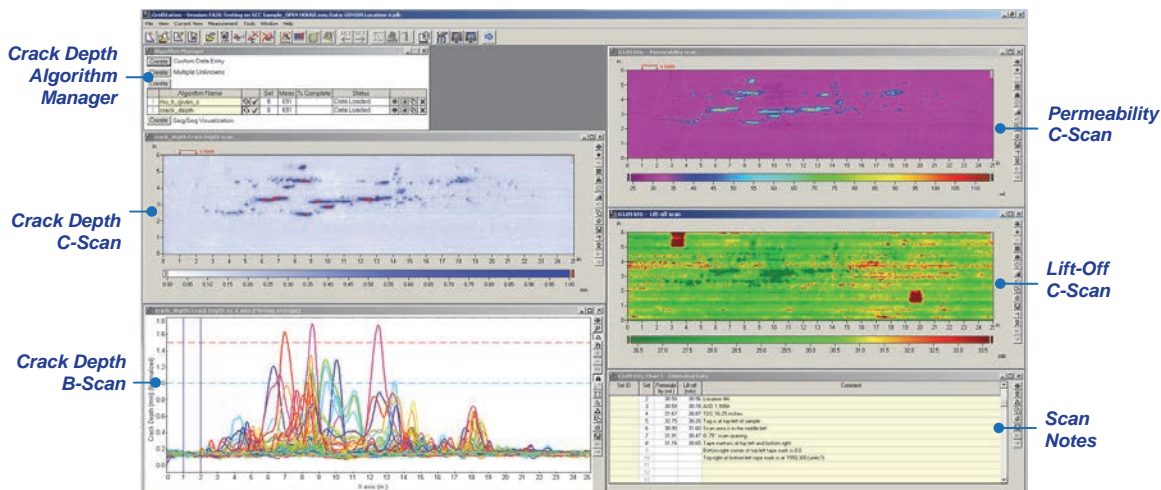
19 Channel Instrument

39 Channel Instrument



Customized NDT Carts

GridStation Software with HyperLattice® Multivariate Inverse Methods



Advanced Eddy-Current Crack Imaging & Depth Sizing Capability with MWM®-Arrays

JENTEK® Sensors

MWM-Array Scanners for SCC Detection through Coatings

- Wide-area scanning arrays for preliminary screening of SCC through coatings (coal tar wrap, epoxy, etc.)
- Scan rates over 20 sq. ft./min (1.86 m²) using JENTEK's GridStation 8200 instrumentation

MWM-Array Scanners for High-Resolution SCC Crack Mapping & Sizing

- High-throughput C-Scan imaging of discrete cracks and/or SCC colonies
- Conformable MWM-Array eddy current sensors configurable for wide range of pipe diameters
- Minimal surface preparation requirements (not affected by coatings, moisture and dirt)

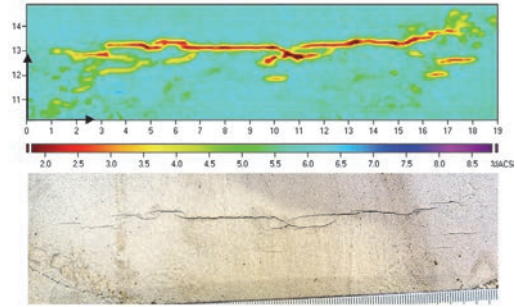
Crack Depth Software Module – JENTEK GridStation Software

- Rapid conversion of MWM-Array response into depth measurements
- Automatic crack interaction capability
- Electronic storage and retrieval of measurement data (as potential MPI replacement)
- Microsoft Windows™ environment with GridStation software for quick and easy report generation

JENTEK 8200 Specifications

General	
Components	39 Channel IN8200 Instrument 39 Channel Inductive Module MWM-Array Eddy Current Sensors Laptop
Weight (instrument only)	6 lbs. (2.72 kg) for 39 Channels

Hardware Specifications	
Instrument power	10-36V DC* *External power adapter provided (runs off of 100-240V, 50-60 Hz AC)
Data Processing	
JENTEK's GridStation software and Windows OS Software with a compatible desktop or laptop configuration	



JENTEK GridStation advanced eddy-current inspection systems have been called **"the gold standard"** of inspections at U.S. Navy Depots

For more information, please visit us at www.jenteksensors.com

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GridStation, MWM, and JENTEK Sensors are registered trademarks of JENTEK Sensors, Inc.

JENTEK Issued patents include U.S. Patent #s: 8,981,018, 8,960,012, 8,928,316, 8,803,515, 8,768,657, 8,494,810, 8,237,433, 8,222,897, 8,050,883, 7,994,781, 7,876,094, 7,812,601, 7,696,748, 7,589,526, 5,533,575, 7,528,598, 7,526,964, 7,518,360, 7,467,057, 7,451,657, 7,451,639, 7,411,390, 7,385,392, 7,348,771, 7,289,913, 7,280,940, 7,230,421, 7,188,532, 7,183,764, 7,161,351, 7,161,350, 7,106,055, 7,095,224, 7,049,811, 6,995,557, 6,992,482, 6,952,095, 6,798,198, 6,784,662, 6,781,387, 6,727,691, 6,657,429, 6,486,673, 6,433,542, 6,420,867, 6,380,747, 6,377,039, 6,351,120, 6,198,279, 6,188,218, 6,144,206, 5,966,011, 5,793,206, 5,629,621, 5,990,677 and RE39,206 (other patents pending).

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